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1	1	("5895264").PN.	USPAT; US-PGPUB	2003/10/20 11:10
2	0	korean with patent with "941273"	JPO; DERWENT	2003/10/20 11:11
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4	0	"1994" and hyundai and (kim adj jae adj gap)	JPO; DERWENT	2003/10/20 11:14
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10	0	(hyundai adj electronics) and (kim with jae with gap)	US-PGPUB	2003/10/20 11:15
11	2748	438/637,640,672,675.ccls.	USPAT; US-PGPUB	2003/10/20 11:47
12	1649	438/637,640,672,675.ccls. and @ad<19990916	USPAT; US-PGPUB	2003/10/20 11:48
13	5045	438/618,253,586,595,639,672.ccls.	USPAT; US-PGPUB	2003/10/20 11:48
14	3072	438/618,253,586,595,639,672.ccls. and @ad<19990916	USPAT; US-PGPUB	2003/10/20 11:48
15	2299	(438/618,253,586,595,639,672.ccls. and @ad<19990916) not (438/637,640,672,675.ccls. and @ad<19990916)	USPAT; US-PGPUB	2003/10/20 12:44
16	16396	(samsung or (kim with in with sung) or (park with joon with soo) or (lee with jung with hyeong) or (kang with hyun with jae))	USPAT; US-PGPUB	2003/10/20 13:02
17	1011	((samsung or (kim with in with sung) or (park with joon with soo) or (lee with jung with hyeong) or (kang with hyun with jae))) and (contact adj hole)	USPAT; US-PGPUB	2003/10/20 13:02
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20	113600	(samsung or (kim with in with sung) or (park with joon with soo) or (lee with jung with hyeong) or (kang with hyun with jae))	EPO; JPO; DERWENT	2003/10/20 13:02
21	1187	((samsung or (kim with in with sung) or (park with joon with soo) or (lee with jung with hyeong) or (kang with hyun with jae))) and (contact adj hole)	EPO; JPO; DERWENT	2003/10/20 13:03
22	80	((((samsung or (kim with in with sung) or (park with joon with soo) or (lee with jung with hyeong) or (kang with hyun with jae))) and (contact adj hole)) and opening	EPO; JPO; DERWENT	2003/10/20 13:03

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[\[Abstract\]](#) [\[PDF Full-Text \(868 KB\)\]](#) **IEEE CNF****1 Influence of short circuits on data of contact and via open circuits determined by a novel weave test structure**

Hess, C.; Weiland, L.H.;
Microelectronic Test Structures, 1995. ICMTS 1995. Proceedings of the 1995 International Conference on , 22-25 March 1995
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[\[Abstract\]](#) [\[PDF Full-Text \(328 KB\)\]](#) **IEEE CNF****2 Plastic packaging stress induced failures in TiW/Al-Si metal to silicide contacts**

Kitagawa, H.; Maeda, T.; Murata, S.; Maki, T.; Kaeriyama, T.; Hyslop, A.; Nishimura, A.;
Reliability Physics Symposium 1988. 26th Annual Proceedings., International , 12-14 April 1988
Page(s): 71 -75

[\[Abstract\]](#) [\[PDF Full-Text \(328 KB\)\]](#) **IEEE CNF****3 New materials and new analysis method for high-efficiency a-Si solar cells**

Nakano, S.; Nakamura, N.; Ninomiya, K.; Tarui, H.; Matsuyama, T.; Nishikuni, M.; Kiyama, S.; Hishikawa, Y.; Dohjo, H.; Tsuda, S.; Ohnishi, M.; Kishi, Y.; Kuwano, Y.;
Photovoltaic Specialists Conference, 1988., Conference Record of the Twentieth IEEE , 26-30 Sept. 1988
Page(s): 123 -128 vol.1

[\[Abstract\]](#) [\[PDF Full-Text \(344 KB\)\]](#) **IEEE CNF**

4 Factors affecting the open circuit voltage in amorphous silicon solar cells

Kim, J.C.; Schwartz, R.J.; Gray, J.L.;

Photovoltaic Specialists Conference, 1993., Conference Record of the Twenty Third IEEE , 10-14 May 1993

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[\[Abstract\]](#) [\[PDF Full-Text \(220 KB\)\]](#) **IEEE CNF**

5 Silicon concentrator solar cells using mass-produced, flat-plate cell fabrication technology

King, R.R.; Mitchell, K.W.; Walle, J.R.; Aldrich, D.L.; Gee, J.M.;

O'Neill, M.; Kaminar, N.; McEntee, J.; Stark, P.;

Photovoltaic Specialists Conference, 1993., Conference Record of the Twenty Third IEEE , 10-14 May 1993

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[\[Abstract\]](#) [\[PDF Full-Text \(452 KB\)\]](#) **IEEE CNF**

6 Si nanoprocess for vertical double-gate MOSFET fabrication

Masahara, M.; Matsukawa, T.; Ishii, K.; Yongxun Liu; Sakamoto, K.;

Kanemaru, S.; Suzuki, E.;

Microprocesses and Nanotechnology Conference, 2002. Digest of Papers. Microprocesses and Nanotechnology 2002. 2002 International , 6-8 Nov. 2002

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[\[Abstract\]](#) [\[PDF Full-Text \(272 KB\)\]](#) **IEEE CNF**

7 Direct tunneling at the front contact of amorphous silicon p-i-n devices

Rubinelli, F.A.;

Electron Devices, IEEE Transactions on , Volume: 39 Issue: 11 , Nov 1992

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[\[Abstract\]](#) [\[PDF Full-Text \(672 KB\)\]](#) **IEEE JNL**

8 Electrographically patterned thin-film silicon transistors

Gleskova, H.; Konenkamp, R.; Wagner, S.; Chen, D.S.;

Electron Device Letters, IEEE , Volume: 17 Issue: 6 , June 1996

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[\[Abstract\]](#) [\[PDF Full-Text \(400 KB\)\]](#) **IEEE JNL**

9 Influence of short circuits on data of contact and via open circuits determined by a novel weave test structure

Hess, C.; Weiland, L.H.;

Semiconductor Manufacturing, IEEE Transactions on , Volume: 9

Issue: 1 , Feb. 1996

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10 Modeling of dry development in bilayer-resist process for 140-nm contact hole patterning

Sung Bo Hwang; Kim, W.D.; Edgar, T.F.;

Semiconductor Manufacturing, IEEE Transactions on , Volume: 15

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11 Longevity of optically activated, high gain GaAs photoconductive semiconductor switches

Loubriel, G.M.; Zutavern, F.J.; Mar, A.; Hjalmanson, H.P.; Baca, A.G.;

O'Malley, M.W.; Helgeson, W.D.; Falk, R.A.; Brown, D.J.;

Plasma Science, IEEE Transactions on , Volume: 26 Issue: 5 , Oct. 1998

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12 Front and back surface fields for point-contact solar cells

King, R.R.; Sinton, R.A.; Swanson, R.M.;

Photovoltaic Specialists Conference, 1988., Conference Record of the Twentieth IEEE , 26-30 Sept. 1988

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[\[Abstract\]](#) [\[PDF Full-Text \(560 KB\)\]](#) **IEEE CNF**

13 A highly reliable multilevel interconnection process for 0.6 μ m CMOS devices

Takata, Y.; Ishii, A.; Matsuura, M.; Ohsaki, A.; Iwasaki, M.; Miyazaki,

J.; Fujiwara, N.; Komori, J.; Katayama, T.; Nakao, S.; Kotani, H.;

VLSI Multilevel Interconnection Conference, 1991, Proceedings.,

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[\[Abstract\]](#) [\[PDF Full-Text \(436 KB\)\]](#) **IEEE CNF**

14 A 0.2- μ m contact filling by 450°C-hydrazine-reduced TiN film with low resistivity

Suzuki, T.; Ohba, T.; Furumura, Y.; Tsuchikawa, H.;

Electron Devices Meeting, 1992. Technical Digest., International , 13-16 Dec. 1992

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[\[Abstract\]](#) [\[PDF Full-Text \(496 KB\)\]](#) **IEEE CNF**

15 0.1 μ m contact metallization with SiH₂F₂-reduced CVD W

Yokoyama, N.; Kumura, S.; Yoshimura, T.; Goto, H.; Kobayashi, N.; Homma, Y.; Takeda, E.;

VLSI Technology, 1992. Digest of Technical Papers. 1992 Symposium on , 2-4 June 1992

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16 Identifying the recombination losses that limit V_{oc} in thin silicon solar cells by bifacial spectral response measurements

Bai, Y.B.; Phillips, J.E.; Barnett, A.M.;

Photovoltaic Energy Conversion, 1994., Conference Record of the Twenty Fourth ; IEEE Photovoltaic Specialists Conference - 1994, 1994 IEEE First World Conference on , Volume: 2 , 5-9 Dec. 1994

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[\[Abstract\]](#) [\[PDF Full-Text \(260 KB\)\]](#) **IEEE CNF**

17 Spectral response modelling of a-Si:H solar cells using accurate light absorption profiles

Stiebig, H.; Kreisel, A.; Winz, K.; Schultz, N.; Beneking, C.; Eickhoff, Th.; Wagner, H.; Meer, M.;

Photovoltaic Energy Conversion, 1994., Conference Record of the Twenty Fourth ; IEEE Photovoltaic Specialists Conference - 1994, 1994 IEEE First World Conference on , Volume: 1 , 5-9 Dec. 1994

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18 Effect of a wide band gap emitter layer and its patterning on the performance of a-Si:H based heterojunction solar cells

Chatterjee, P.;

Photovoltaic Energy Conversion, 1994., Conference Record of the Twenty Fourth ; IEEE Photovoltaic Specialists Conference - 1994, 1994 IEEE First World Conference on , Volume: 1 , 5-9 Dec. 1994
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19 Reliability improvement in high aspect ratio contacts and vias filled with blanket tungsten CVD film

Fukuda, N.; Saito, T.; Suzuki, Y.; Fujiwara, T.; Yamaguchi, H.; Owada, N.;

Reliability Physics Symposium, 1995. 33rd Annual Proceedings., IEEE International , 4-6 April 1995

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20 Recrystallized silicon on SiO₂-layers for thin film solar cells

Hebling, C.; Gaffke, R.; Lanyi, P.; Lautenschlager, H.; Schetter, C.; Wagner, B.; Lutz, F.;

Photovoltaic Specialists Conference, 1996., Conference Record of the Twenty Fifth IEEE , 13-17 May 1996

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[\[Abstract\]](#) [\[PDF Full-Text \(796 KB\)\]](#) **IEEE CNF**

21 17.1% efficient truncated-pyramid inversion-layer silicon solar cells

Grauvogl, M.; Aberle, A.G.; Hezel, R.;

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22 Fabrication and characterisation of 662-mV open-circuit voltage high-efficiency inversion-layer silicon solar cells

Kuhlmann, B.; Aberle, A.G.; Meyer, R.; Hubner, A.; Hampe, C.; Hezel, R.;

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23 Suppression of dislocation multiplication inside contact holes

Peng, Y.C.; Chen, L.J.; Hsieh, Y.F.;

Ion Implantation Technology Proceedings, 1998 International Conference on , Volume: 2 , 22-26 June 1998

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24 Vacuum packaging using anodic bonding and emission characteristics of FED

Duck-Jung Lee; Byeong-Kwon Ju; Jee-Won Jeong; Hoon Kim;

Sung-Jae Jung; Jin Jang; Myung-Hwan Oh;

Information Display, 1999. ASID '99. Proceedings of the 5th Asian Symposium on , 17-19 March 1999

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25 10×10 cm² screen printed back contact cell with a selective emitter

Kress, A.; Tolle, R.; Bruton, T.; Fath, P.; Bucher, E.;

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26 Insights into the nonideal behavior of CdS/CdTe solar cells*McMahon, T.J.; Fahrenbruch, A.L.;*

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Device Research Conference, 2000. Conference Digest. 58th DRC, 19-21 June 2000

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3,200 V*Chih-Fang Huang; Cooper, J.A., Jr.;*

Power Semiconductor Devices and ICs, 2002. Proceedings of the 14th International Symposium on , 4-7 June 2002

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Electron Devices, IEEE Transactions on , Volume: 37 Issue: 12 , Dec. 1990

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Electron Devices, IEEE Transactions on , Volume: 37 Issue: 2 , Feb. 1990

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[\[Abstract\]](#) [\[PDF Full-Text \(264 KB\)\]](#) **IEEE JNL****34 GaN/AlGaN p-channel inverted heter structure JFET**

Shatalov, M.; Simin, G.; Jianping Zhang; Adivarahan, V.; Koudymov, A.; Pachipulusu, R.; Asif Khan, M.;
Electron Device Letters, IEEE , Volume: 23 Issue: 8 , Aug. 2002
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